

# SUCCESS IS BEING EXCELLENT AT WHAT YOU DO

Learn how to get the most from your PDF-4+ database from the database experts.

## Join ICDD at our free PDF-4+ workshop during the XXI Conference on Applied Crystallography Zakopane, Poland

24–25 September 2009

Institute of Material Science, University of Silesia

Workshop registration is via the Conference home page ([www.crystallography.us.edu.pl](http://www.crystallography.us.edu.pl)).

Participants are encouraged to bring their laptops to this tutorial. ICDD will install a trial version of the PDF-4+ to facilitate a hands-on workshop.

**Speakers:** Cyrus Crowder, ICDD Principal Scientist  
Matteo Leoni, University of Trento, ICDD Regional Co-chair for Europe

### Getting Started Tutorial Thursday 24 September

This tutorial will discuss and demonstrate the basic functions of DDView+, thus enabling the user to distill the huge number of entries in PDF-4+ to a manageable selected subset.

- ▲ Searching: selecting search criteria, then viewing/manipulating search results
- ▲ History: combining search criteria
- ▲ Diffraction Pattern: viewing and manipulating digitized pattern graphs
- ▲ Advanced GUI tricks

### Expert's Tutorial Friday 25 September

Learn shortcuts that speed the selection and filtering of entries for comparison with experimental laboratory data and methods that graphically exhibit advanced functions of pattern information.

- ▲ Integral Index: a similarity index comparing user's full experimental data to patterns in PDF-4+
- ▲ 3D structures and bond distances/angles
- ▲ Advanced data mining: how to solve problems faster with XRD data
- ▲ Using Sieve+: effective identification strategies, optimizing search criteria

### Problem Solving Examples

- ▲ Published solutions to difficult problems using PDF-4+

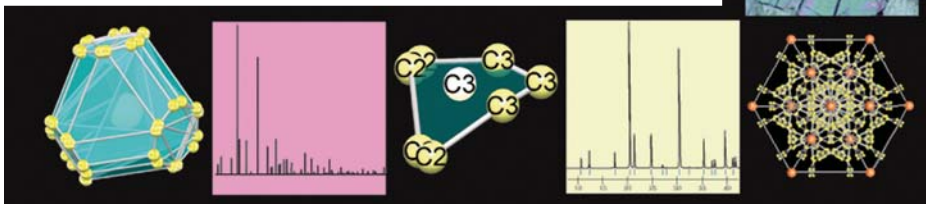
### Applications

- ▲ Integral index and the use of total pattern matching
- ▲ Applications to nanomaterials

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